MUN'I RECC	U.S. Department of Commerce
ORM PTO-1595 (Bajal (Ba)	03013543
I To the Honorable Commissioner of Patents and Trademarks: Please reco	
Name of conveying party(ies): <u>Date</u>	2. Name and address of receiving party(ies):
Optonics, Inc. October 27, 2004	Name: Credence Systems Corporation
	Internal Address: Street Address: <u>1421 California Circle, 95035</u>
Additional name(s) of conveying party(ies) attached? YesX_No 3. Nature of conveyance:	City: <u>Milpitas</u> State: <u>CA</u> Zip: <u>95035</u>
X_AssignmentMerger	Additional name(s) & address(es) attached? Yes X_ No
Security Agreement Change of Name	
OtherExecution Date:	
4. Application number(s) or registration number(s):	
If this document is being filed together with a new application, the execution	on date of the application is: (Date of Filing)
A. Patent Application No.(s) 10/379,950	RF 2
B. Patent No. Additional numbers attached? Yes X No	on date of the application is: (Date of Filing)
Name and address of party to whom correspondence concerning document should be mailed:	6. Total number of applications and patents involved 1
Name:Joseph Bach	7. Total fee (37 C.F.R. 3.41) \$_40.00
Internal Address: <u>JBPatents.com</u>	X Enclosed 1022
Street Address: 17460 Lakeview Drive	Authorized to be charged to deposit account
City: <u>Morgan Hill</u> State: <u>CA</u> Zip: <u>95037</u>	8. Deposit account number:
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9. Statement and signature.	
To the best of my knowledge and belief, the foregoing information is true	and correct and any attached copy is a true copy of the original docume
JOSEPH BACH Reg No. 37,771 Name of Person Signing	<u>May 24, 2005</u> Date
Т	otal number of pages including cover sheet, attachments and document
Commissioner of Patents &	h required cover sheet information to: Trademarks, Box Assignments n, D.C. 20231
2005 ECDOPER 00000028 10379950	
8021 40.00 OP	

PATENT REEL: 016606 FRAME: 0121

• Form PIC-1595 (Rev. (-93) (2MB No. 0551-0011 (exp. 4/94)		U.S. Department of Commerc Patent And Trademark Offic
To the Honorable Commissioner of Patents and Trade	emarks: Please record une attachive angent of c	or copy thereof.
1. Name of conveying party(ies): <u>Date</u>	2. Name and address of receiv er 27, 2004 Name: <u>Credence, Inc.</u> Internal Address:	
Additional name(s) of conveying party(ies) attached? 3. Nature of conveyance: X Assignment Merger Security Agreement Change of Name OtherExecutio	Yes X No City: Milpitas State: Additional name(s) & address(e)	<u>CA</u> Zip: <u>95035</u>
 4. Application number(s) or registration number(s): If this document is being filed together with a new app A. Patent Application No.(s) 10/379,950 B. Patent No. Additional numbers attached?Yes 	Dication, the execution date of the application is: _ (Date	of Filing)
5. Name and address of party to whom corresponder document should be mailed:	nce concerning 6. Total number of applications	and patents involved: 1^{1-1}
Name: Joseph Bach	7. Total fee (37 C.F.R. 3.41)	\$_40.00
Internal Address: <u>JBPatents.com</u>	_X_ Enclosed	
	Authorized to be charge	d to deposit account
Street Address: <u>17460 Lakeview Drive</u> City: <u>Morgan Hill</u> State: <u>CA</u> Zip: <u>95</u>	037 8. Deposit account num	iber:
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9. Statement and signature. To the best of my knowledge and belief, the foregoing	g information is true and correct and any attached copy	is a true copy of the original docu
JOSEPH BACH Reg No. 37,771		<u>November 1, 2004</u>
Name of Person Signing	Signature Total number of pages including cov	Date er sheet, attachments and docum
Mail documer Commi 2004 DBYRNE 00000006 10379950 :8021 40.00 DP	its to be recorded with required cover sheet information ssioner of Patents & Trademarks, Box Assignments Washington, D.C. 20231	to:
J:\FORMS\272 (AUGUST 20, 1993)		

ASSIGNMENT OF PATENTS AND PATENT APPLICATIONS

WHEREAS, Optonics, Inc., hereinafter called "ASSIGNOR", a California corporation having its principal place of business at 2593 Coast Avenue, Suite 100, Mountain View, California 94043, is the assignee of certain patents and patent applications listed in Appendix A attached herewith and comprising two pages.

AND WHEREAS Credence Systems Corporation, a Delaware corporation, having it's principal place of business at 1421 California Circle Milpitas, California 95035, together with any successors, legal representatives or assigns thereof, called "ASSIGNEE" wants to acquire the entire right, title and interest in and to said patents and patent applications.

NOW, THEREFORE, in consideration of the sum of \$1.00, the receipt thereof is hereby acknowledged, and other good and valuable consideration, the receipt of which is hereby acknowledged, ASSIGNOR have sold, assigned, transferred and set over, and do hereby sell, assign, transfer and set over to ASSIGNEE the entire right, title and interest in and to said improvements, and said application and all divisions and continuations thereof, and all United States Letters Patents which may be granted thereon and all reissues, reexaminations and extensions thereof, and all priority rights under all available International Agreements, Treaties and Conventions for the protection of Intellectual property in its various forms in every participating country, and all applications for patents (including related rights such as utility-model registrations, inventor's certificates, and the like) heretofore or hereafter filed for said improvements in any foreign countries, and all patents (including all continuations, divisions, extensions, renewals, substitutes, and reissues thereof) granted for said improvements in any foreign countries; and we hereby authorize and request the United States Commissioner of Patents and Trademarks, and any officials of foreign countries whose duty it is to issue patents on applications as aforesaid, to issue all patents for said improvements to ASSIGNEE in accordance with the terms of this Assignment.

AND ASSIGNOR HEREBY covenant that we have full right to convey the entire interest herein assigned, and that we have not executed, and will not execute, any agreement in conflict herewith.

IN TESTIMONY WHEREOF, I hereunto set my hand this 27day of October, 2004

Signature of ASSIGNOR:

For Optonics Inc.

By: Israel Niv

Title: President and CEO

STATE OF CALIFORNIA

OPTONICS INC

10/52/5004 13:11 *2202082*

PATENT REEL: 016606 FRAME: 0123

APPENDIX A				1 of 2
Application No.	Country	Title	Patent No.	
09/995,548	United States	Time Resolved Non-Invasive Diagnostics System	6,621,275	
10/457,968	United States	Time Resolved Non-Invasive Diagnostics System		
PCT/US01/38431	Patent Cooperation Treaty	Time Resolved Non-Invasive Diagnostics System		
2797156.3	European Palent Convention	Time Resolved Non-Invasive Diagnostics System		
2003-547980	Japan	Time Resolved Non-Invasive Diagnostics System		
2004-7007251	South Korea	Time Resolved Non-Invasive Diagnostics System		
91134678	Taiwan	Time Resolved Non-Invasive Diagnostics System		
10/052,011	United States	BI-Convex Solid Immersion Lens	6,594,086	
10/440,866	United States	Bi-Convex Solid Immersion Lens	6,778,327	
10/883,542	United States	Bi-Convex Solid Immersion Lens		
PCT/US02/39538	Patent Cooperation Treaty	Bi-Convex Solid Immersion Lens		
2004-7007230	South Korea	BI-CONVEX Solid Intmersion Lens		
2822785.9	China P.R.	Bi-Convex Solid Immersion Lens		
91137365	Taiwan	Bi-Convex Solid Immersion Lens		
10/379,950	United States	Universal Platform for Integrated Circuit Analysis		
10/255,345	United States	Solid Immersion Lens Landing System		
10/930,454	United States	Solid Immersion Lens Landing System		
10/294,434	United States	Avalanche Photo Diode for Pholon Counting Applications	6,720,588	
10/721,915	United States	Avalanche Photo Diode for Photon Counting Applications and Method Thereof	6,797,581	
91133774	Taiwan	Avalamatie Photo Diode for Photon Counting Applications	201324	
PCT/US02/37366	Patent Cooperation Treaty	Avalanche Photo Diode for Photon Counting Applications and Method Thereof		
2804016	European Patent Convention	Avaianche Photo Diode for Photon Counting Applications and Method Thereof		
2003-648319	Japan	Avalanche Photo Didde for Photon Counting Applications and wethod Thereof		
91133774	Taiwan	Avalanche Photo Diode for Photon Counting Applications and Method Thereof		
2820685.1	China P.R.	Avalanche Photo Diode for Photon Counting Applications and Method Thereof		
2004-7007361	South Korea	Avalanche Photo Diode for Photon Counting Applications and Method Thereof		
10/222,107	United States	Spray Cooling Thermal Management System and Method for Semiconductor Probing, Diagnostics, and Failure Anatysis		
60/385,524	United States	Inter & Intra Chip Signal Communication System for IC Devices and Method Using Hot Electron Photoemission		
10/379,925	United States	Spray Cooling and Transparent Cooling Plate Thermal Management System		
PCT/US03/036547	Patent Cooperation	Spray Cooling and Transparent Cooling Plate Thermal Management System		
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APPENDIX A				2 of 2
Application No.	Country	Trite	Patent No.	
92132629	Taiwan	Spray Cooling and Transparent Cooling Plate Thermal Management System		
10/613,593	United States	Time Resolved Emission Shectra Analyn's System		
10/408,988	United States	System and Method for Calibration of Testing Equipment using Device Photoemission		
PCT/US04/010728	Patent Cooperation	System and Method for Calibration of Testing Equipment using Device Photoemission		
93109727	Taiwan	System and Method for Calibration of Testing Equipment using Device Photoemission		
10/719,880	United States	Shutter Blade Position Detection		
10/845,013	United States	Beacon Circuit for Photo Emission Vottage Analysis		
10/872,595	United States	Integrated APD and Lens Assembly		
10/912,896	United States	Light Beam Apparatus and Method for Orthogonal Alighment of Specimen		
10/229,181	United States	Apparatus and Method for Dynamic Diagnostic Testing of Integrated Circuits		
92101517	Taiwan	Apparatus and Method for Dynamic Diagnostic Testing of Integrated Circuits		
03713326.1-1236	European Patent	Apparatus and Method for Dynamic Diagnostic Testing of Integrated Circuits	aw 4-	
	Convention			
03602724.0.	China P.R.	Apparatus and Method for Dynamic Diagnostic Testing of Integrated Circuits		
2003-556568	Japan	Apparatus and Method for Dynamic Diagnostic Testing of Integrated Circuits		
2004-7011746	South Korea	Apparatus and Method for Dynamic Diagnostic Testing of Integrated Circuits		
10/341,721	United States	Apparatus and Method for Measuring Characteristics of Dynamic Electrical Signals in Integrated		

RECORDED: 05/27/2005

PATENT REEL: 016606 FRAME: 0125

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